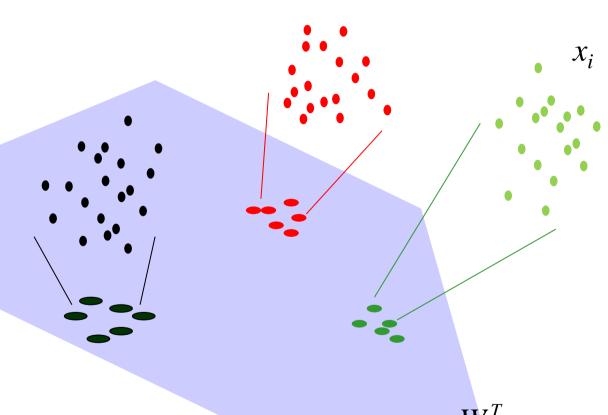




#### Fisher Linear Discriminant



Goal: find plane (subspace) that "shrinks" each class while separating all classes.

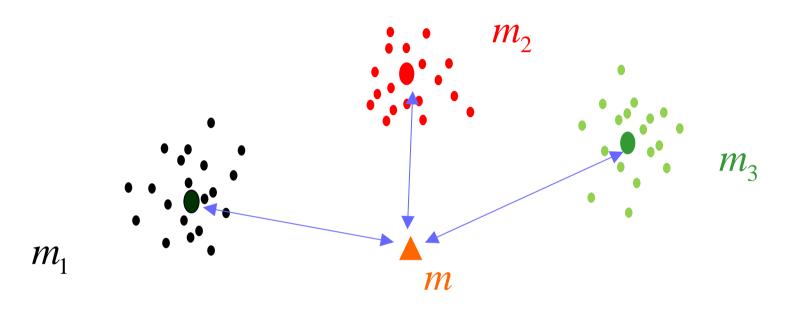


$$y_i = W^T x_i$$

#### Fisher Linear Discriminant



Class separation: between-class scatter matrix



 $n_i$ : # samples in class  $\omega_i$ 

 $m_i$ : mean of class  $\omega_i$ 

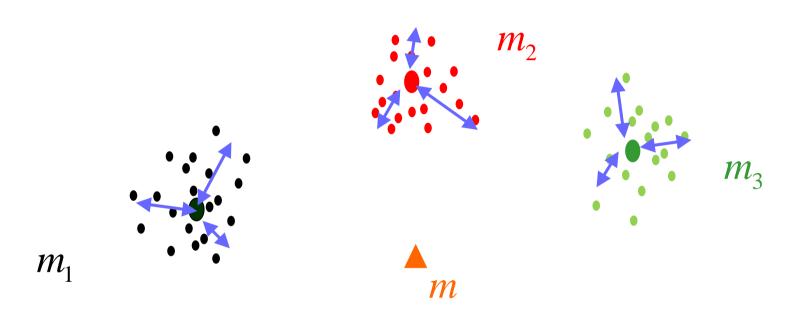
m: global mean

$$S_B = \sum_{i=1}^C n_i (m_i - m)(m_i - m)^T$$

#### Fisher Linear Discriminant or LDA



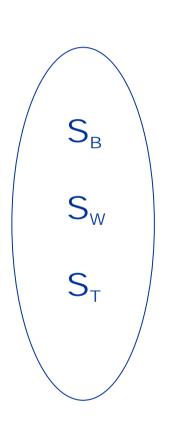
Class spread: within-class scatter matrix



$$S_W = \sum_{i=1}^C \sum_{x \in \omega_i} (x - m_i) (x - m_i)^T$$



#### Scatter matrices after projection



$$x \rightarrow y = W^T x$$

$$S_{B}' = W^{T}S_{B}W$$

$$S_{W}' = W^{T}S_{W}W$$

$$S_{T}' = W^{T}S_{T}W$$

$$\mathbf{S}_T = \mathbf{S}_B + \mathbf{S}_W$$

Total scatter matrix

#### Fisher's Criterion



$$\boldsymbol{J}_{F} = \frac{|\mathbf{W}^{T}\mathbf{S}_{B}\mathbf{W}|}{|\mathbf{W}^{T}\mathbf{S}_{W}\mathbf{W}|}$$

- Numerator is the between-class scatter matrix after projection (i.e.  $y_i$ )
- Denominator is the within-class scatter matrix after projection (i.e. y<sub>i</sub>)
- W is the projection matrix.
- Goal: find W to maximize Fisher's Criterion
- Recall PCA:

$$J = \frac{|\mathbf{W}^{\mathsf{T}} \mathbf{S}_{T} \mathbf{W}|}{|\mathbf{W}^{\mathsf{T}} \mathbf{W}|}$$

# LDA





It can be shown that the solution is:

$$\mathbf{S}_{B}\mathbf{w} = \lambda \mathbf{S}_{W}\mathbf{w}$$

- This is the Generalized Eigenvalue Problem
- If Sw is invertible, then

$$\mathbf{S}_{W}^{-1}\mathbf{S}_{B}\mathbf{w} = \lambda\mathbf{w}$$

which is the regular eigenvalue problem

### LDA



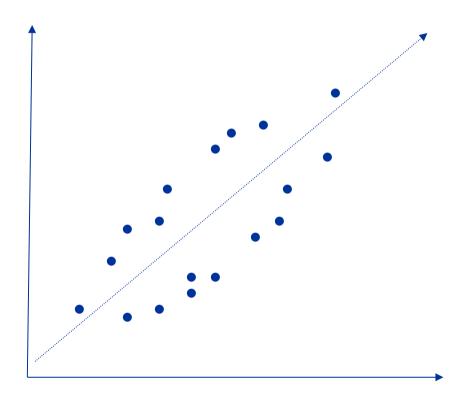
- There will be up to C-1 eigenvectors.
- But these won't be mutually orthogonal
  - O Because  $\mathbf{S}_{W}^{-1}\mathbf{S}_{B}$  may not be symmetric.
- The eigenvectors form a subspace that maximizes the Fisher Criterion.
- Put them into the matrix W, then compute the feature as:

$$\mathbf{y} = \mathbf{W}^T \mathbf{x}$$

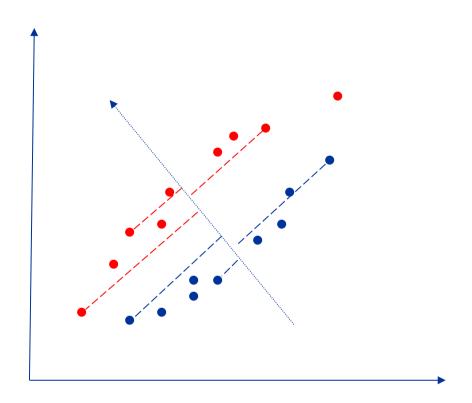












LDA:  $\max |S_B'| / |S_W'|$ 

#### Questions about the FLD



- How to compare  $J_F$ ?
  - O What is the best possible  $J_F$ ?
  - O Answer: +∞
- Does maximizing  $J_F$  perfectly separate classes?
  - If not, under what conditions can classes be perfectly separated?
  - $\bigcirc$  Answer: require D >= N-1 and linearly independence
- Can these conditions be satisfied in practice?
  - Usually, e.g. face images, but not digit recognition
- How are class patterns (vectors) distributed in the subspace W?
  - As vertices of a regular simplex

# Whitened FLD (WFLD) [Zhang&Sim: [1], also CVPR 06, PAMI Of School of Computing

Whiten the data with P:

Whitening 
$$\mathbf{S}_{T} = \mathbf{S}_{B} + \mathbf{S}_{w}$$
matrix  $\mathbf{S}_{T} = \mathbf{U}\mathbf{D}^{2}\mathbf{U}^{T}$ 

$$\mathbf{P} = \mathbf{U}\mathbf{D}^{-1}$$

$$\mathbf{\tilde{x}}_{i} = \mathbf{P}^{T}\mathbf{x}_{i}$$

$$\Rightarrow \mathbf{\tilde{S}}_{T} = \mathbf{P}^{T}\mathbf{S}_{T}\mathbf{P} = \mathbf{I}$$

$$\mathbf{P}^{T}(\mathbf{S}_{B} + \mathbf{S}_{w})\mathbf{P} = \mathbf{I}$$

$$\mathbf{\tilde{S}}_{B} + \mathbf{\tilde{S}}_{w} = \mathbf{I}$$

$$\mathbf{\tilde{S}}_{w} = \mathbf{I} - \mathbf{\tilde{S}}_{B}$$

• Let ebe eigenvector of  $\widetilde{\mathbf{S}}_{\scriptscriptstyle B}$  with eigenvalue  $\lambda_{\scriptscriptstyle B}$ 

$$\widetilde{\mathbf{S}}_{W} \mathbf{e} = (\mathbf{I} - \widetilde{\mathbf{S}}_{B}) \mathbf{e}$$

$$= \mathbf{e} - \lambda_{B} \mathbf{e} = (1 - \lambda_{B}) \mathbf{e}$$

$$= \lambda_{W} \mathbf{e}$$

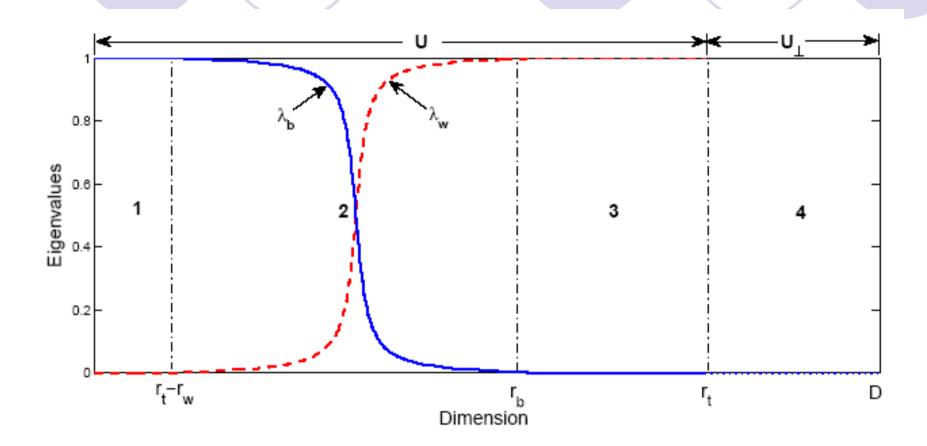
So  $\widetilde{\mathbf{S}}_B$  and  $\widetilde{\mathbf{S}}_W$  share the same eigenvectors, and their eigenvalues sum to 1.

Moreover:

$$\frac{\lambda_{B}}{\lambda_{w}} = J_{F}$$

#### Discriminant Subspace Analysis





- 1. Identity Space:  $J_F = +\infty$
- 2. Mixed Space:  $0 < J_F < +\infty$
- 3. Variation Space:  $J_F = 0$
- 4. Null Space: no discrim. info

#### **Identity Space**



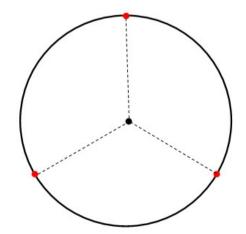
- Definition
  - Osubspace 1: eigenvectors with  $\lambda_b = 1$ ,  $\lambda_w = 0$
  - The most discriminant subspace  $\mathbf{y}_1 = \mathbf{V}_1^T \mathbf{P}^T \mathbf{x}$
- Properties (Theorem 1 in paper)
  - No within-class variation
    - Samples from one class project onto one point (a.k.a Identity Vector).
  - Classes are cleanly separated.
    - Samples from one class will not project onto another class as long as they have different class means.

#### **Identity Space**

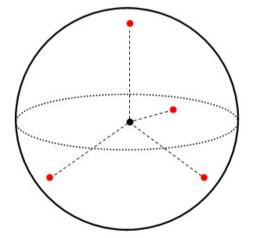




- Geometric Structure (Theorem 3 in paper)
  - C Identity Vectors are equidistant and distributed on a C-1 dimensional sphere.
  - The distance between classes has been maximized.



Three Identity Vectors distributed on a 2D circle



Four Identity Vectors distributed on a 3D sphere

### Variation Space



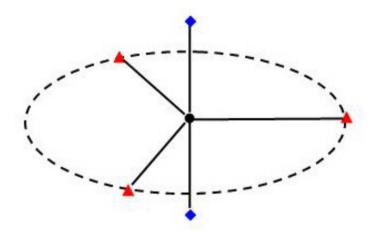
- Definition
  - Osubspace 3: eigenvectors with  $\lambda_b = 0$ ,  $\lambda_w = 1$
  - The least discriminant subspace  $\mathbf{y}_3 = \mathbf{V}_3^T \mathbf{P}^T \mathbf{x}$
- Property (Theorems 4 & 6 in paper)
  - All class means project to zero.
  - The within-class variation of each class lie in orthogonal subspaces.

#### Variation Space



#### Geometric Structure

- After projecting onto Variation Space, any two classes are orthogonal to each other.
- For each class, samples are equally distributed over a hypersphere (for 1D case, it is a straight line.).

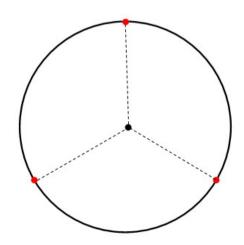


Class One has two samples lying on a vertical line, and both are orthogonal to Class Two, which has three samples evenly distributed on a circle.

### Discriminability of Identity Space

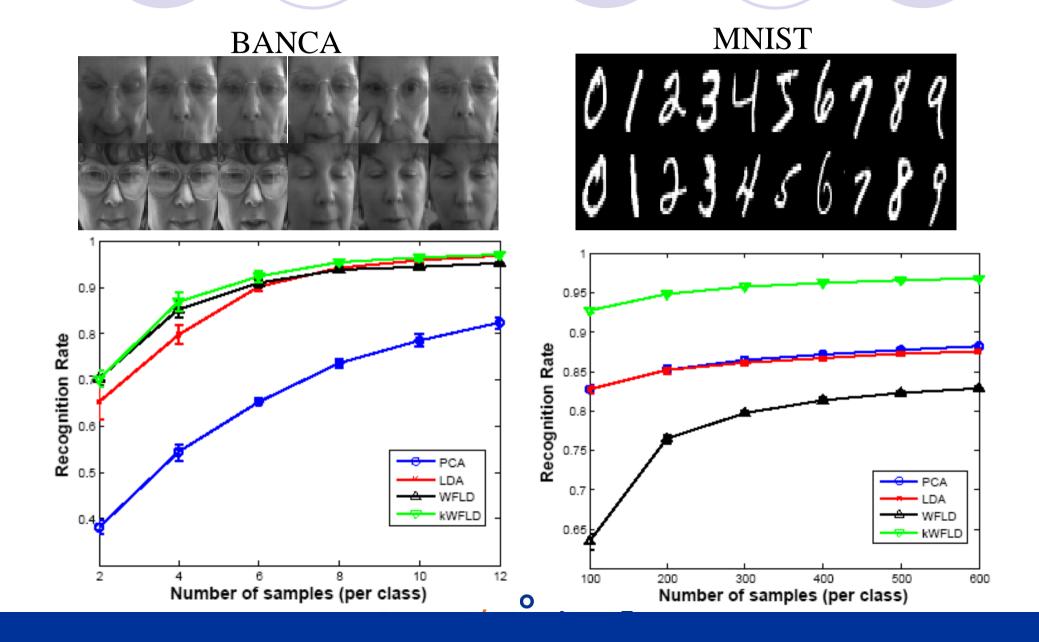


- Project query point onto Identity Space.
- Find nearest class mean
  - Euclidean or cosine distance



#### Discriminability of Identity Space

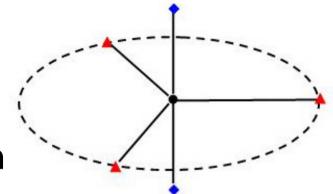




#### Discriminability of Variation Space Of Computing

- No means for classification!
  - Not according to the Fisher Criterion

$$\boldsymbol{J}_{F} = \frac{|\mathbf{W}^{T}\mathbf{S}_{B}\mathbf{W}|}{|\mathbf{W}^{T}\mathbf{S}_{W}\mathbf{W}|}$$

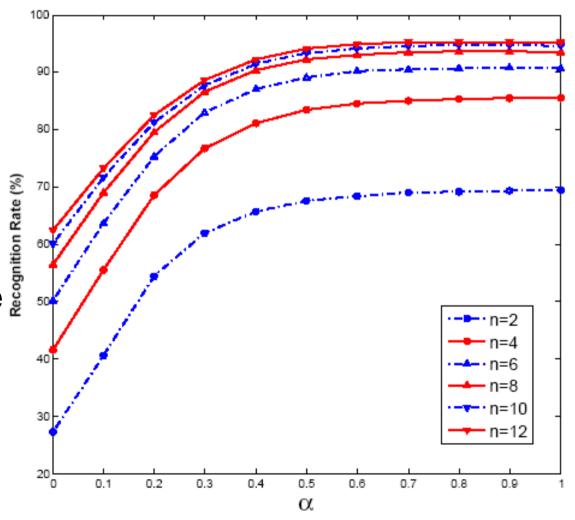


- But in WFLD, within-class variations of all classes occupy orthogonal subspaces.
  - We can use this for classification, even if class means are identical!

## Discriminability of Variation Space National University of Singapore O

- Distance is a weighted sum of  $d_i$  and  $d_{ij}$ 
  - d: Euclidean distance to class mean in Identity Space Space  $d_V$ : distance to subspace
  - in Variation Space

$$d = \alpha d_I + (1 - \alpha) d_V$$



#### Other subspace methods



Independent Components Analysis (ICA)

$$y = W^T x$$

- Components of y are statistically indep., not just uncorrelated.
- W is not orthogonal
- Algorithm makes lots of approximations, so unclear whether resulting components are indeed indep.
- Applied in Blind Source Separation problem
  - Cocktail-party problem: separate who said what

#### Other subspace methods



- Canonical Correlation Analysis (CCA)
  - O Give vectors **x**, **y** (possibly different dimensions)
  - $\bigcirc$  Find w such that Y'=w<sup>T</sup>y, X'=w<sup>T</sup>x are most correlated.
- Use this to model Y' = RX'
  - Applied in estimating depth map from color image [3]



Original surface



Reconstructed surface



Original face patch



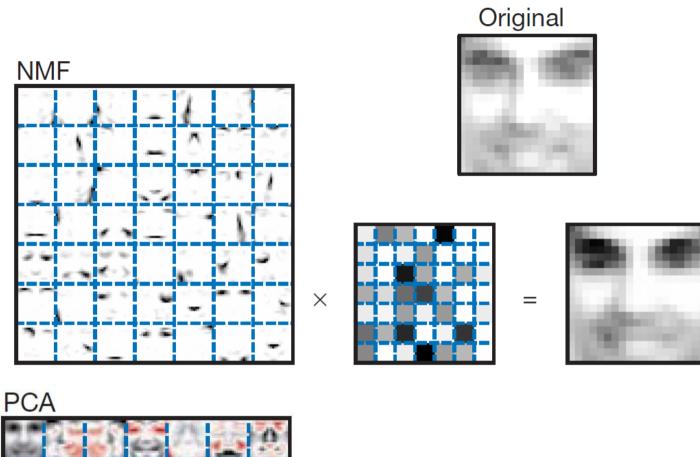
Reconstructed face patch

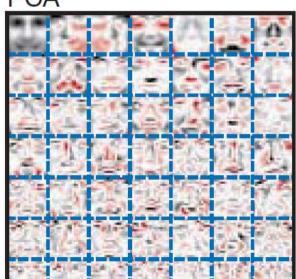
#### Other subspace methods

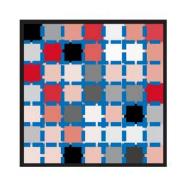


- Non-negative Matrix Factorization (NMF) [2]
- In PCA, given data matrix X, find X = WY
  - Entries in W and Y can be negative
- In NMF, find X = WH
  - Entries in W and H must be non-negative
  - Iterative algorithm to find W
  - W is not orthogonal

## NMF







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#### References



- [1] Identity and Variation Spaces: Revisiting the Fisher Linear Discriminant. Sheng Zhang, Terence Sim, Mei-Chen Yeh. Subspace 2009, at ICCV 2009.
- [2] Learning the parts of objects by non-negative matrix factorization. Daniel D. Lee & H. Sebastian Seung. Nature, vol. 401, Oct. 1999
- [3] Estimation of Face Depth Maps from Color Textures using Canonical Correlation Analysis. Michael Reiter, Ren'e Donner, Georg Langs, and Horst Bischof. Computer Vision Winter Workshop 2006.
- [4] An Introduction to Independent Component Analysis and Blind Source Separation. Lucas C. Parra. Tech. Rep., Sarnoff Corporation, 1999.